

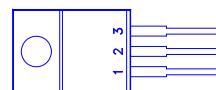
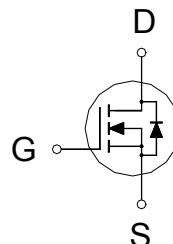
**NIKO-SEM****N-Channel Enhancement Mode  
Field Effect Transistor****P0908AT**

TO-220

Halogen-Free &amp; Lead-Free

**PRODUCT SUMMARY**

$V_{(BR)DSS}$	$R_{DS(ON)}$	$I_D$
80V	9mΩ	64A



1. GATE
2. DRAIN
3. SOURCE

**ABSOLUTE MAXIMUM RATINGS ( $T_A = 25^\circ C$  Unless Otherwise Noted)**

PARAMETERS/TEST CONDITIONS	SYMBOL	LIMITS	UNITS
Drain-Source Voltage	$V_{DS}$	80	V
Gate-Source Voltage	$V_{GS}$	$\pm 20$	V
Continuous Drain Current $T_C = 25^\circ C$	$I_D$	64	A
$T_C = 100^\circ C$	$I_D$	41	
Pulsed Drain Current <sup>1</sup>	$I_{DM}$	160	
Avalanche Current	$I_{AS}$	49	
Avalanche Energy	$E_{AS}$	120	mJ
Power Dissipation $T_C = 25^\circ C$	$P_D$	83	W
$T_C = 100^\circ C$	$P_D$	33	
Operating Junction & Storage Temperature Range	$T_j, T_{stg}$	-55 to 150	° C

**THERMAL RESISTANCE RATINGS**

THERMAL RESISTANCE	SYMBOL	TYPICAL	MAXIMUM	UNITS
Junction-to-Case	$R_{\theta JC}$	1.5	50	° C / W
Junction-to-Ambient	$R_{\theta JA}$			

<sup>1</sup>Pulse width limited by maximum junction temperature.

**ELECTRICAL CHARACTERISTICS ( $T_J = 25^\circ C$ , Unless Otherwise Noted)**

PARAMETER	SYMBOL	TEST CONDITIONS	LIMITS			UNITS
			MIN	TYP	MAX	
<b>STATIC</b>						
Drain-Source Breakdown Voltage	$V_{(BR)DSS}$	$V_{GS} = 0V, I_D = 250\mu A$	80			V
Gate Threshold Voltage	$V_{GS(th)}$	$V_{DS} = V_{GS}, I_D = 250\mu A$	2	3.4	4	
Gate-Body Leakage	$I_{GSS}$	$V_{DS} = 0V, V_{GS} = \pm 20V$			$\pm 100$	nA
Zero Gate Voltage Drain Current	$I_{DSS}$	$V_{DS} = 64V, V_{GS} = 0V$			1	$\mu A$
		$V_{DS} = 60V, V_{GS} = 0V, T_J = 125^\circ C$			10	

**NIKO-SEM****N-Channel Enhancement Mode  
Field Effect Transistor****P0908AT**

TO-220

Halogen-Free &amp; Lead-Free

Drain-Source On-State Resistance <sup>1</sup>	R <sub>DS(ON)</sub>	V <sub>GS</sub> = 10V, I <sub>D</sub> = 20A	7	9	mΩ
		V <sub>GS</sub> = 7V, I <sub>D</sub> = 15A	8.1	12	
Forward Transconductance <sup>1</sup>	g <sub>fs</sub>	V <sub>DS</sub> = 5V, I <sub>D</sub> = 20A	57		S
<b>DYNAMIC</b>					
Input Capacitance	C <sub>iss</sub>	V <sub>GS</sub> = 0V, V <sub>DS</sub> = 25V, f = 1MHz	2853		pF
Output Capacitance	C <sub>oss</sub>		355		
Reverse Transfer Capacitance	C <sub>rss</sub>		199		
Gate Resistance	R <sub>g</sub>		0.9		
Total Gate Charge <sup>2</sup>	Q <sub>g</sub>	V <sub>DS</sub> = 15V, I <sub>D</sub> = 20A	55		nC
Gate-Source Charge <sup>2</sup>	Q <sub>gs</sub>		41.5		
Gate-Drain Charge <sup>2</sup>	Q <sub>gd</sub>		15.3		
Turn-On Delay Time <sup>2</sup>	t <sub>d(on)</sub>		19.4		
Rise Time <sup>2</sup>	t <sub>r</sub>	V <sub>DD</sub> = 15V, I <sub>D</sub> ≈ 20A, V <sub>GS</sub> = 10V, R <sub>GEN</sub> = 6Ω	37		nS
Turn-Off Delay Time <sup>2</sup>	t <sub>d(off)</sub>		42		
Fall Time <sup>2</sup>	t <sub>f</sub>		63		
			48		

**SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS (T<sub>J</sub> = 25 °C)**

Continuous Current	I <sub>S</sub>			59	A
Forward Voltage <sup>1</sup>	V <sub>SD</sub>	I <sub>F</sub> = 20A, V <sub>GS</sub> = 0V		1.4	V
Reverse Recovery Time	t <sub>rr</sub>	I <sub>F</sub> = 20A , dI <sub>S</sub> /dt= 100A/μs	35		nS
Reverse Recovery Charge	Q <sub>rr</sub>		40		nC

<sup>1</sup>Pulse test : Pulse Width ≤ 300 μsec, Duty Cycle ≤ 2%.<sup>2</sup>Independent of operating temperature.

**NIKO-SEM**

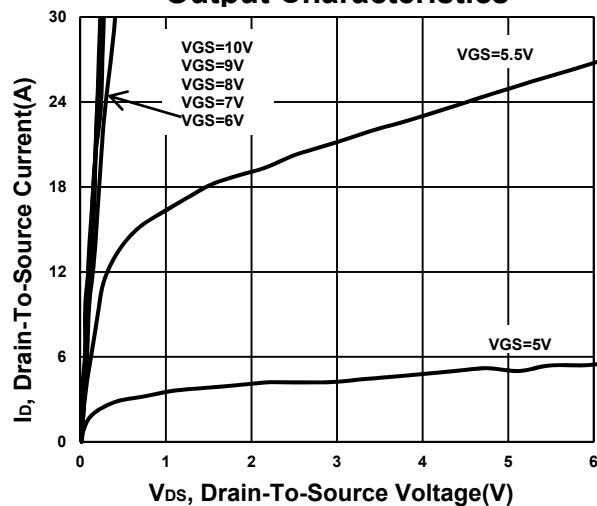
**N-Channel Enhancement Mode  
Field Effect Transistor**

**P0908AT**

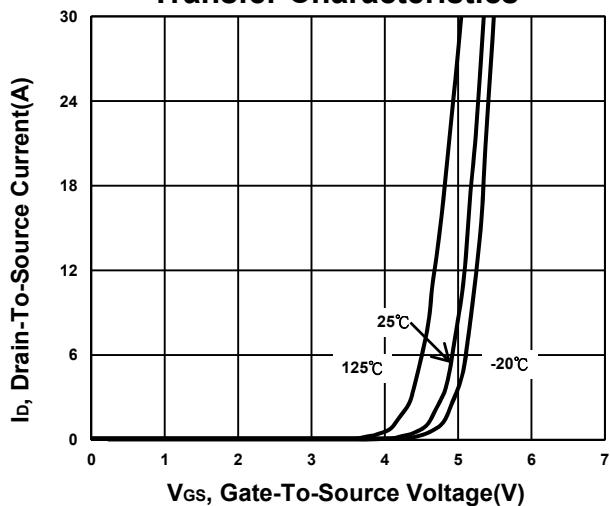
**TO-220**

**Halogen-Free & Lead-Free**

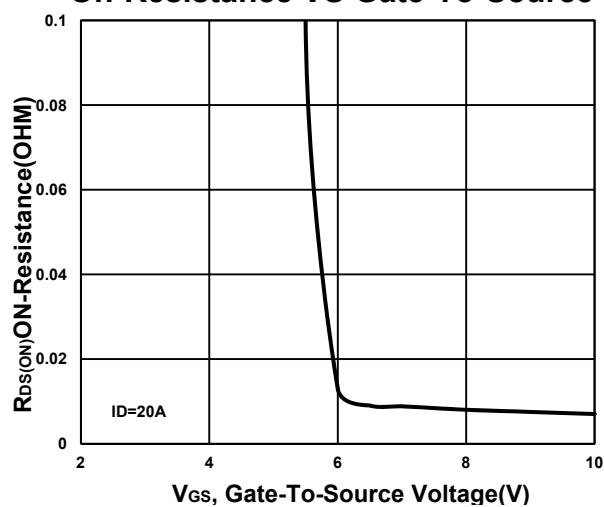
**Output Characteristics**



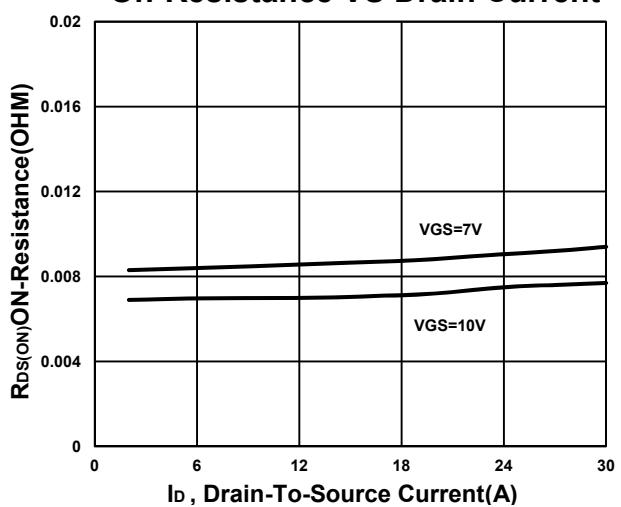
**Transfer Characteristics**



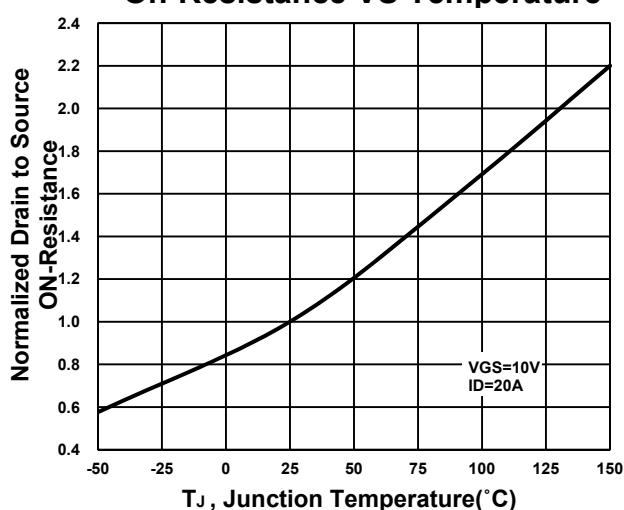
**On-Resistance VS Gate-To-Source**



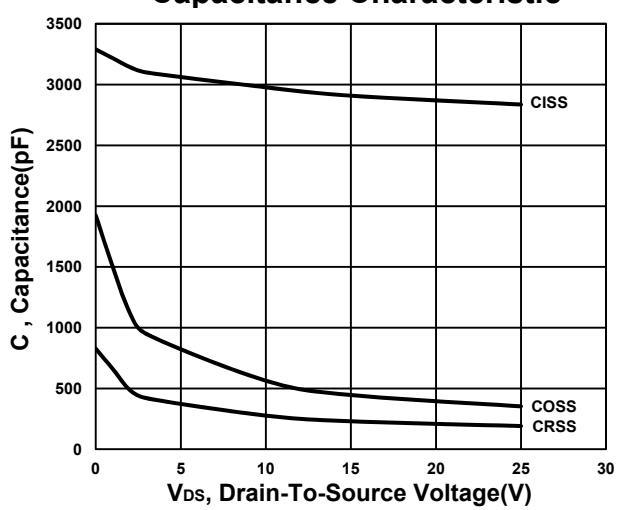
**On-Resistance VS Drain Current**



**On-Resistance VS Temperature**



**Capacitance Characteristic**



**NIKO-SEM**

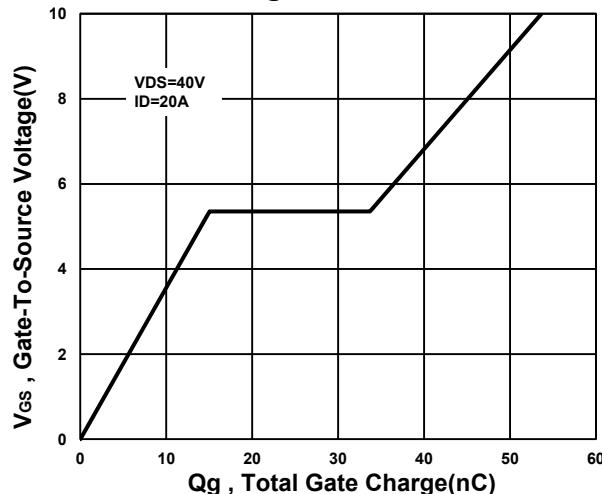
**N-Channel Enhancement Mode  
Field Effect Transistor**

**P0908AT**

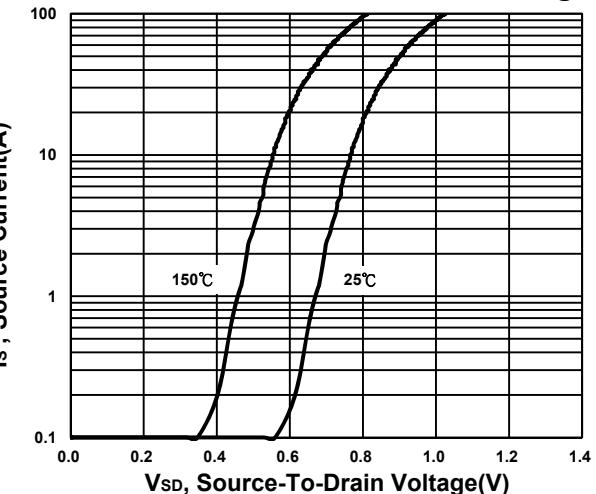
**TO-220**

**Halogen-Free & Lead-Free**

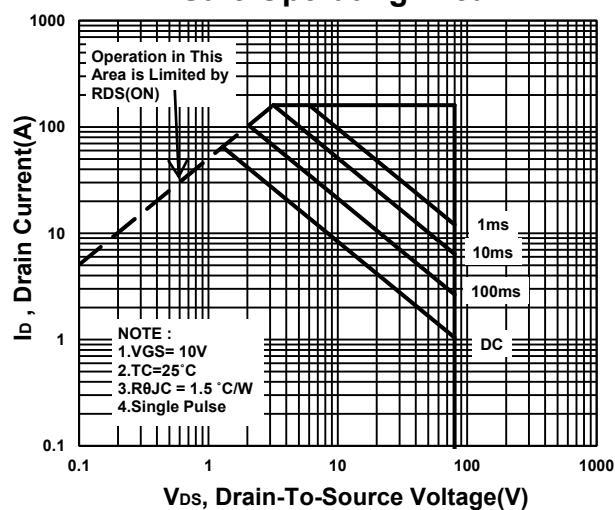
**Gate charge Characteristics**



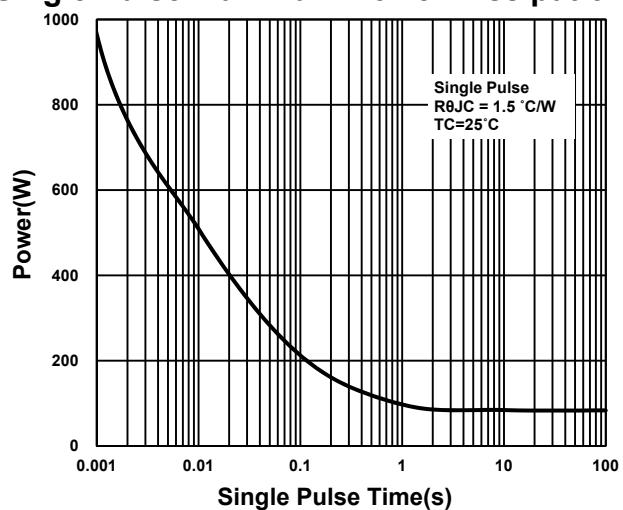
**Source-Drain Diode Forward Voltage**



**Safe Operating Area**



**Single Pulse Maximum Power Dissipation**



**Transient Thermal Response Curve**

